

Supplementary Materials: Combined Pulsed RF GD-OES and HAXPES for Quantified Depth Profiling through Coatings

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Table S1. Evolution of the position and FWHM parameters for In 3d_{5/2}, P 2p_{3/2} and P 2s for XPS and HAXPES measurements.

		Photopeak		In 3d _{5/2}		P 2p _{3/2}		P 2s	
		Contribution	Position (eV)	FWHM (eV)	Position (eV)	FWHM (eV)	Position (eV)	FWHM (eV)	
XPS	Reference	In P	444.5 ± 0.1	0.79 ± 0.02	128.7 ± 0.1	0.59 ± 0.02	186.5 ± 0.1	1.53 ± 0.02	
		oxide	445.3 ± 0.1	1.18 ± 0.02	132.9 ± 0.1	1.09 ± 0.02	190.6 ± 0.1	2.35 ± 0.02	
	GD-OES crater	In P	444.1 ± 0.1	1.04 ± 0.02	128.4 ± 0.1	0.83 ± 0.02	186.2 ± 0.1	1.64 ± 0.02	
		oxide	445.1 ± 0.1	1.30 ± 0.02	132.9 ± 0.1	1.21 ± 0.02	190.3 ± 0.1	2.34 ± 0.02	
HAXPES	Reference	New	N/A	N/A	128.9 ± 0.1	0.83 ± 0.02	187.0 ± 0.1	1.64 ± 0.02	
	GD-OES crater	In P	444.5 ± 0.2	1.48 ± 0.04	129.0 ± 0.2	1.65 ± 0.04	186.5 ± 0.2	1.53 ± 0.04	
		In P	444.3 ± 0.2	1.49 ± 0.04	128.5 ± 0.2	1.72 ± 0.04	186.4 ± 0.2	2.06 ± 0.04	

Table S2. Evolution of the position and FWHM parameters for In 2p_{3/2} and P 1s for HAXPES measurements.

		Photopeak		In 2p _{3/2}		P 1s	
		Contribution	Position (eV)	FWHM (eV)	Position (eV)	FWHM (eV)	
HAXPES	Reference	In P	3731.7 ± 0.2	3.02 ± 0.04	2142.9 ± 0.2	1.66 ± 0.04	
		In P	3731.1 ± 0.2	3.05 ± 0.04	2142.2 ± 0.2	1.75 ± 0.04	